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IN THE U.S. PATENT AND TRADEMARK OFFICE

August 31, 2005

Applicants : Takaomi NAKAYAMA et al
For : TREATING SOLUTION FOR SURFACE TREATMENT OF
METAL AND A METHOD FOR SURFACE TREATMENT

PCT International Application No.: PCT/JP2003/015868

PCT International Filing Date: December 11, 2003

U.S. Application No.

(if known, see 37 CFR 1.5): 10/537 329

Atty. Docket No.: 4626.P0002US

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INFORMATION DISCLOSURE STATEMENT

Sir:

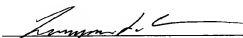
In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is Form PTO-1449 and the references cited thereon. These references are mentioned in Applicants' specification. Further comment at this point in time should not be necessary.

JP 8-176841 corresponds to WO 96/19595. JP 9-25436 corresponds to EP 0 838 537. JP 9-31404 corresponds to U.S. 6 059 896. JP 2000-199077 corresponds to U.S. 6 361 833. JP 5-195244 corresponds to U.S. 5 449 414. WO 02/103080 corresponds to U.S. 2004/0244874.

Since this application was filed after June 30, 2003, Applicants hereby accept the USPTO waiver of the requirement under 37 CFR 1.98(a)(2)(i) for submitting a copy of each cited U.S. patent [1273 Off. Gaz. Pat. Off. 55, 8/05/2003].

Further consideration is respectfully solicited.

Respectfully submitted,


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Encl: Form PTO-1449 and one copy of each non-U.S. reference
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INFORMATION
DISCLOSURE
CITATION

Applicant: Takaomi NAKAYAMA et al
 Serial No.: 10/537 329 Filed: June 1, 2005
 Conf. No.: Unknown Atty. Docket No.: 4626.P0002US
 Group: Unknown

SEP 02 2005

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AB	4 273 592	06-16-1981	KELLY
	AB	4 313 769	02-02-1982	FRELIN et al
	AC	5 380 374	01-10-1995	TOMLINSON
	AD	5 449 414	09-12-1995	DOLAN
	AE	6 059 896	05-09-2000	EHARA et al
	AF	6 361 833 B1	03-26-2002	NAKADA et al
	AG	2004/0244874 A1	12-9-2004	NAKAYAMA et al

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AI	JP 2000-204485	07-25-2000	SHIMAKURA	X
	AJ	JP 56-136978	10-26-1981	FUJIMOTO et al	Abstract
	AK	JP 8-176841	07-09-1996		
	AL	WO 96/19595	06-27-1996	IINO et al	
	AM	JP 9-25436	01-28-1997		
	AN	EP 0 838 537 A1	04-29-1998	KANDA	
	AO	JP 9-31404	02-04-1997		
	AP	JP 2000-199077	07-18-2000		
	AQ	JP 5 195 244	08-03-1993		
	AR	WO 02/103080 A1	12-27-2002		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AS	
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EXAMINER SIGNATURE		DATE CONSIDERED
/Lois Zheng/		02/26/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.